

<b>Notice of References Cited</b>	Application/Control No. 09/904,317	Applicant(s)/Patent Under Reexamination OHATA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,819,286 A	10-1998	Yang et al.	707/1
*	B	US-5,826,270 A	10-1998	Rutkowski et al.	707/10
*	C	US-5,893,053 A	04-1999	Trueblood, John	702/187
*	D	US-5,946,687 A	08-1999	Gehani et al.	707/10
*	E	US-6,108,554 A	08-2000	Kawamoto, Yoji	455/456.5
*	F	US-6,307,641 B1	10-2001	Hamano et al.	358/1.15
*	G	US-2001/0054041 A1	12-2001	Chang, Lan	707/5
*	H	US-6,330,576 B1	12-2001	Mochizuki et al.	715/529
*	I	US-6,405,034 B1	06-2002	Tijerino, Yuri Adrian	455/414.3
*	J	US-6,665,442 B2	12-2003	Sekiguchi et al.	382/224
*	K	US-6,920,488	07-2005	Le Pennec et al.	709/219
*	L	US-6,928,424 B2	08-2005	Honda, Hachiro	707/1
*	M	US-7,031,965 B1	04-2006	Moriya et al.	707/10

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
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**NON-PATENT DOCUMENTS**

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,928,306 A	07-1999	France et al.	701/207
*	B	US-6,314,295 B1	11-2001	Kawamoto, Yoji	455/456.2
*	C	US-2001/0039541 A1	11-2001	Okawa et al.	707/3
*	D	US-6,442,538 B1	08-2002	Nojima, Hiroshi	707/1
*	E	US-2002/0112003 A1	08-2002	Glorikian, Harry A.	709/203
*	F	US-2003/0060211 A1	03-2003	CHERN et al.	455/456
*	G	US-6,636,803 B1	10-2003	Hartz et al.	701/208
*	H	US-6,658,389 B1	12-2003	Alpdemir, Ahmet	704/275
*	I	US-6,748,383 B1	06-2004	Wada et al.	707/10
*	J	US-6,789,102 B2	09-2004	Gotou et al.	709/203
*	K	US-2004/0250083 A1	12-2004	Schwab, Barry	713/182
*	L	US-7,024,208 B2	04-2006	Kaise, Kunitake	455/456.3
*	M	US-7,031,729 B2	04-2006	Kawamoto, Yoji	455/456.6

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
	T					

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,212,475 B1	04-2001	France et al.	701/214
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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